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P-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A) ^d	Q _g (Typ.)			
- 30	0.0125 at V _{GS} = - 10 V	- 11.6	22 nC			
	0.018 at V _{GS} = - 4.5 V	- 10	22 110			

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SO-8

Top View

P-Channel MOSFET

FEATURES

- Halogen-free According to IEC 61249-2-21 **Available**
- TrenchFET® Power MOSFET
- 100 % R_g Tested
 100 % UIS Tested

COMPLIANT HALOGEN **FREE**

APPLICATIONS

- · Load Switches
 - Notebook PCs
 - Desktop PCs

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	- 30	V	
Gate-Source Voltage		V _{GS}	± 20	v
	T _C = 25 °C		- 11.6	
Continuous Drain Current (T _J = 150 °C)	T _C = 70 °C	1 .	- 10.5	
Continuous Diain Current (1) = 150 °C)	T _A = 25 °C	I _D	- 8.7 ^{a, b}	
	T _A = 70 °C		- 7.7 ^{a, b}	A
Pulsed Drain Current	I _{DM}	- 40	A	
Continuous Course Dunin Die de Course	T _C = 25 °C	1	- 4.6	
Continuous Source-Drain Diode Current	T _A = 25 °C	- I _S -	2.0 ^{a, b}	
Avalanche Current	1 0411	I _{AS}	- 20	
Single-Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	20	mJ
	T _C = 25 °C		5.6	
Maximum Davian Dissination	T _C = 70 °C	1 ,	3.6	١٨/
Maximum Power Dissipation	T _A = 25 °C	P _D	2.5 ^{a, b}	W
	T _A = 70 °C	1	1.6 ^{a, b}	
Operating Junction and Storage Temperature Rang	T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{a, c}	t ≤ 10 s	R _{thJA}	39	50	°C/W		
Maximum Junction-to-Foot	Steady State	R _{thJF}	18	22	C/VV		

- a. Surface mounted on 1" x 1" FR4 board.
- c. Maximum under Steady State conditions is 85 °C/W. d. Based on $T_{\rm C}$ = 25 °C.



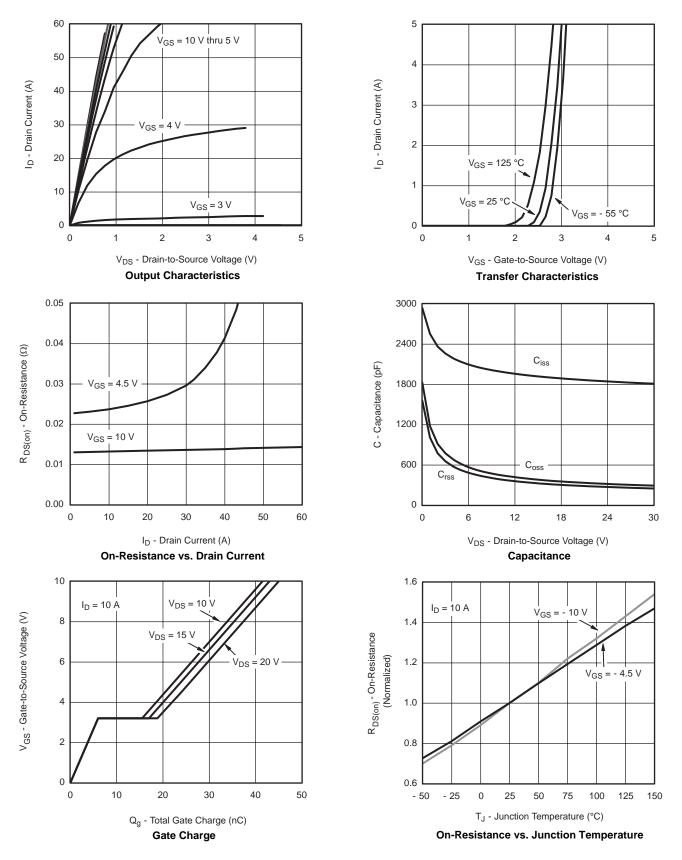
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V, } I_D = -250 \mu\text{A}$	- 30			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = - 250 μA		- 31		\//00
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	η = - 250 μΑ		5.5		mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 1.0		- 3.0	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			± 100	nA
Zara Cata Valtaga Drain Current	I _{DSS}	V _{DS} = - 30 V, V _{GS} = 0 V	- 1		- 1	
Zero Gate Voltage Drain Current		V _{DS} = - 30 V, V _{GS} = 0 V, T _J = 55 °C			- 5	μA
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge -10 \text{ V}, V_{GS} = -10 \text{ V}$	- 30			Α
	В	V _{GS} = - 10 V, I _D = - 10 A		0.011	Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = -4.5 \text{ V}, I_D = -7 \text{ A}$		0.012		
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 10 V, I _D = - 10 A		23		S
Dynamic ^b	_					
Input Capacitance	C _{iss}			1960		pF
Output Capacitance	C _{oss}	$V_{DS} = -15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		380		
Reverse Transfer Capacitance	C _{rss}			325		
Total Gate Charge	Q_g $V_{DS} = -15 \text{ V}, V_{GS} = -10 \text{ V}, I_D = -10$	$V_{DS} = -15 \text{ V}, V_{GS} = -10 \text{ V}, I_{D} = -10 \text{ A}$		43	65	
			22	33		
Gate-Source Charge	Q_{gs}	$V_{DS} = -15 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -10 \text{ A}$		6		nC
Gate-Drain Charge	Q _{gd}			11		
Gate Resistance	R_g	f = 1 MHz	0.3	1.3	2.5	Ω
Turn-On Delay Time	t _{d(on)}			11	22	
Rise Time	t _r	V_{DD} = - 15 V, R_L = 3 Ω		13	25	
Turn-Off DelayTime	t _{d(off)}	$I_D \cong -5 \text{ A}, V_{GEN} = -10 \text{ V}, R_g = 1 \Omega$		32	50	
Fall Time	t _f			9	18	
Turn-On Delay Time	t _{d(on)}			44	70	ns
Rise Time	t _r	V_{DD} = - 15 V, R_L = 3 Ω		100	160	
Turn-Off DelayTime	t _{d(off)}	$I_D \cong -5 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_g = 1 \Omega$		28	50	
Fall Time	t _f			15	30	
Drain-Source Body Diode Characterist	ics					
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			- 4.6	^
Pulse Diode Forward Current	I _{SM}				- 50	A
Body Diode Voltage	V _{SD}	I _S = -2 A, V _{GS} = 0 V		- 0.75	- 1.2	V
Body Diode Reverse Recovery Time	t _{rr}			28	45	ns
Body Diode Reverse Recovery Charge	Q _{rr}	1 2 A dl/dt 100 A/vs T 25 °C		20	40	nC
Reverse Recovery Fall Time	t _a	$I_F = -2 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$	13		nc	
Reverse Recovery Rise Time	t _b	1		15		ns

Notes:

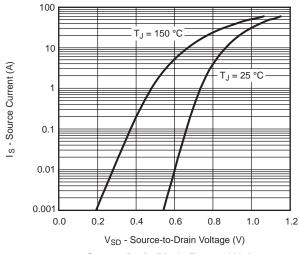
- a. Pulse test; pulse width \leq 300 μ s, duty cycle \leq 2 %.
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

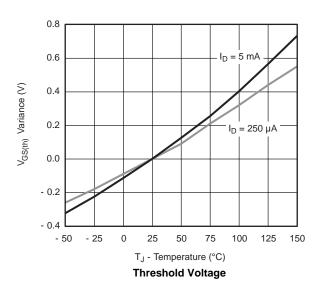


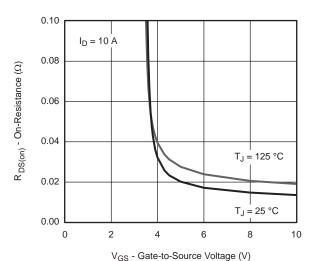




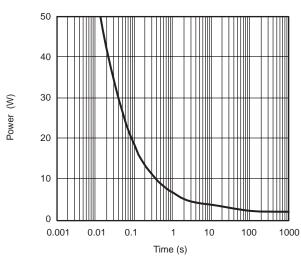


Source-Drain Diode Forward Voltage

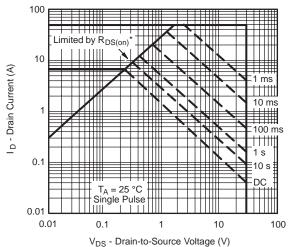




On-Resistance vs. Gate-to-Source Voltage



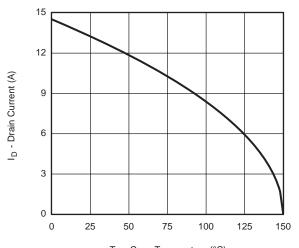
Single Pulse Power, Junction-to-Ambient



* V_{GS} > minimum V_{GS} at which R_{DS(on)} is specified

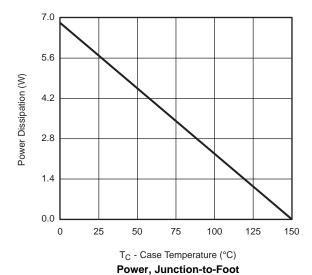
Safe Operating Area

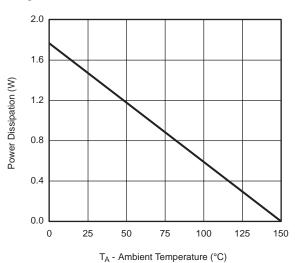




 $T_{\mbox{\scriptsize C}}$ - Case Temperature (°C)

Current Derating*

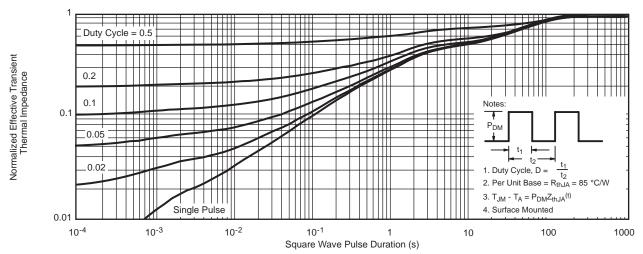




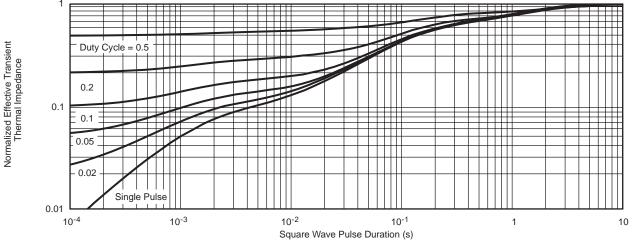
Power Derating, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





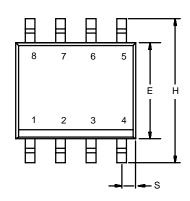
Normalized Thermal Transient Impedance, Junction-to-Ambient

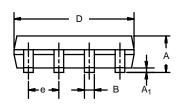


Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012







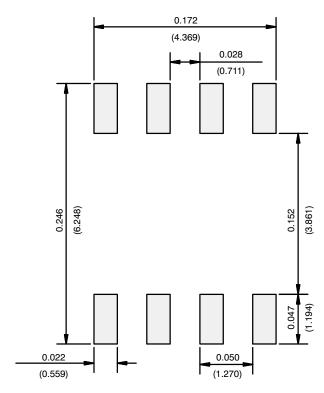
	MILLIMETERS		INCHES			
DIM	Min	Max	Min	Max		
Α	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
Е	3.80	4.00	0.150	0.157		
е	1.27	1.27 BSC		0.050 BSC		
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
FCN: C-06527-Rev 11-Sen-06						

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)

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